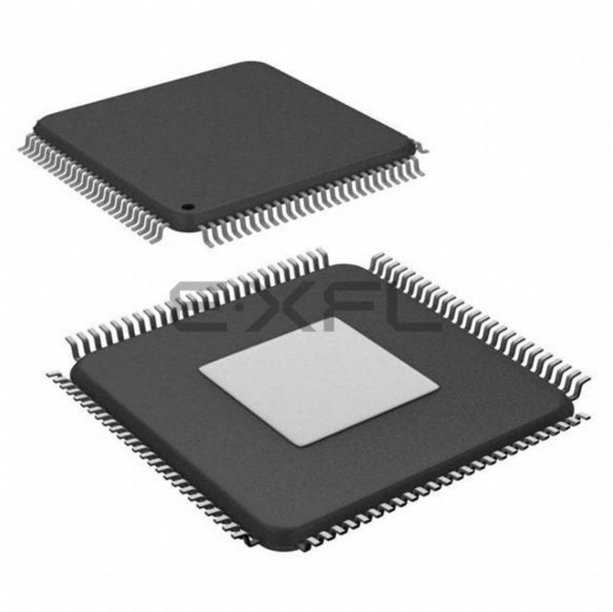
Infineon Technologies - XE164FM24F80LAAFXUMA1 Datasheet



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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	C166SV2
Core Size	16-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	76
Program Memory Size	192KB (192K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	24K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xe164fm24f80laafxuma1

XE164xM
Revision History: V2.1, 2011-07

Previous Version(s):
V2.0, 2009-03
V1.3, 2008-11
V1.2, 2008-09
V1.1, 2008-06 Preliminary
V1.0, 2008-06 (Intermediate version)

Page	Subjects (major changes since last revisions)
39	ID registers added
86	ADC capacitances corrected (typ. vs. max.)
90	Conditions relaxed for ’f_{INT} Range for f_{WU} adapted according to PCN 2010-013-A Added startup time from power-on t_{SPO}
127	Quality declarations added

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mcdocu.comments@infineon.com

16-Bit Single-Chip
Real Time Signal Controller
XE164xM (XE166 Family)

1 Summary of Features

For a quick overview and easy reference, the features of the XE164xM are summarized here.

- High-performance CPU with five-stage pipeline and MPU
  - 12.5 ns instruction cycle at 80 MHz CPU clock (single-cycle execution)
  - One-cycle 32-bit addition and subtraction with 40-bit result
  - One-cycle multiplication (16 × 16 bit)
  - Background division (32 / 16 bit) in 21 cycles
  - One-cycle multiply-and-accumulate (MAC) instructions
  - Enhanced Boolean bit manipulation facilities
  - Zero-cycle jump execution
  - Additional instructions to support HLL and operating systems
  - Register-based design with multiple variable register banks
  - Fast context switching support with two additional local register banks
  - 16 Mbytes total linear address space for code and data
  - 1024 Bytes on-chip special function register area (C166 Family compatible)
  - Integrated Memory Protection Unit (MPU)
- Interrupt system with 16 priority levels for up to 96 sources
  - Selectable external inputs for interrupt generation and wake-up
  - Fastest sample-rate 12.5 ns
- Eight-channel interrupt-driven single-cycle data transfer with Peripheral Event Controller (PEC), 24-bit pointers cover total address space
- Clock generation from internal or external clock sources, using on-chip PLL or prescaler
- Hardware CRC-Checker with Programmable Polynomial to Supervise On-Chip Memory Areas
- On-chip memory modules
  - 8 Kbytes on-chip stand-by RAM (SBRAM)
  - 2 Kbytes on-chip dual-port RAM (DPRAM)
  - Up to 16 Kbytes on-chip data SRAM (DSRAM)
  - Up to 32 Kbytes on-chip program/data SRAM (PSRAM)
  - Up to 576 Kbytes on-chip program memory (Flash memory)
  - Memory content protection through Error Correction Code (ECC)
- On-Chip Peripheral Modules
  - Multi-functional general purpose timer unit with 5 timers
  - 16-channel general purpose capture/compare unit (CAPCOM2)

Table 5 Pin Definitions and Functions (cont d)

Pin	Symbol	Ctrl.	Type	Function
90	P1.4	O0 / I	St/B	**Bit 4 of Port 1, General Purpose Input/Output**
	CCU62_COUT61	O1	St/B	**CCU62 Channel 1 Output**
	U1C1_SELO4	O2	St/B	**USIC1 Channel 1 Select/Control 4 Output**
	U2C0_SELO5	O3	St/B	**USIC2 Channel 0 Select/Control 5 Output**
	A12	OH	St/B	**External Bus Interface Address Line 12**
	U2C0_DX2B	I	St/B	**USIC2 Channel 0 Shift Control Input**
91	P10.15	O0 / I	St/B	**Bit 15 of Port 10, General Purpose Input/Output**
	U1C0_SELO2	O1	St/B	**USIC1 Channel 0 Select/Control 2 Output**
	U0C1_DOUT	O2	St/B	**USIC0 Channel 1 Shift Data Output**
	U1C0_DOUT	O3	St/B	**USIC1 Channel 0 Shift Data Output**
	ALE	OH	St/B	**External Bus Interf. Addr. Latch Enable Output**
	U0C1_DX1C	I	St/B	**USIC0 Channel 1 Shift Clock Input**
92	P1.5	O0 / I	St/B	**Bit 5 of Port 1, General Purpose Input/Output**
	CCU62_COUT60	O1	St/B	**CCU62 Channel 0 Output**
	U1C1_SELO3	O2	St/B	**USIC1 Channel 1 Select/Control 3 Output**
	$\overline{\text{BRKOUT}}$	O3	St/B	**OCDS Break Signal Output**
	A13	OH	St/B	**External Bus Interface Address Line 13**
	U2C0_DX0C	I	St/B	**USIC2 Channel 0 Shift Data Input**

Table 5 Pin Definitions and Functions (cont d)

Pin	Symbol	Ctrl.	Type	Function
97	$\overline{\text{PORST}}$	I	In/B	**Power On Reset Input** A low level at this pin resets the XE164xM completely. A spike filter suppresses input pulses <10 ns. Input pulses >100 ns safely pass the filter. The minimum duration for a safe recognition should be 120 ns. An internal pull-up device will hold this pin high when nothing is driving it.
98	$\overline{\text{ESR1}}$	O0 / I	St/B	**External Service Request 1** After power-up, an internal weak pull-up device holds this pin high when nothing is driving it.
	RxDC0E	I	St/B	**CAN Node 0 Receive Data Input**
	U1C0_DX0F	I	St/B	**USIC1 Channel 0 Shift Data Input**
	U1C0_DX2C	I	St/B	**USIC1 Channel 0 Shift Control Input**
	U1C1_DX0C	I	St/B	**USIC1 Channel 1 Shift Data Input**
	U1C1_DX2B	I	St/B	**USIC1 Channel 1 Shift Control Input**
	U2C1_DX2C	I	St/B	**USIC2 Channel 1 Shift Control Input**
99	$\overline{\text{ESR0}}$	O0 / I	St/B	**External Service Request 0** After power-up, $\overline{\text{ESR0}}$ operates as open-drain bidirectional reset with a weak pull-up.
	U1C0_DX0E	I	St/B	**USIC1 Channel 0 Shift Data Input**
	U1C0_DX2B	I	St/B	**USIC1 Channel 0 Shift Control Input**
10	V_{DDIM}	-	PS/M	**Digital Core Supply Voltage for Domain M** Decouple with a ceramic capacitor, see Data Sheet for details.
38, 64, 88	V_{DDI1}	-	PS/1	**Digital Core Supply Voltage for Domain 1** Decouple with a ceramic capacitor, see Data Sheet for details. All V_{DDI1} pins must be connected to each other.
14	V_{DDPA}	-	PS/A	**Digital Pad Supply Voltage for Domain A** Connect decoupling capacitors to adjacent $V_{\text{DDP}}/V_{\text{SS}}$ pin pairs as close as possible to the pins. *Note: The A/D_Converters and ports P5, P6 and P15 are fed from supply voltage* V_{DDPA}.

Table 5 Pin Definitions and Functions (cont d)

Pin	Symbol	Ctrl.	Type	Function
2, 25, 27, 50, 52, 75, 77, 100	V_{DDPB}	-	PS/B	**Digital Pad Supply Voltage for Domain B** Connect decoupling capacitors to adjacent V_{DDP}/V_{SS} pin pairs as close as possible to the pins. *Note: The on-chip voltage regulators and all ports except P5, P6 and P15 are fed from supply voltage* V_{DDPB}.
1, 26, 51, 76	V_{SS}	-	PS/--	**Digital Ground** All V_{SS} pins must be connected to the ground-line or ground-plane. *Note: Also the exposed pad is connected internally to* V_{SS}. *To improve the EMC behavior, it is recommended to connect the exposed pad to the board ground.* *For thermal aspects, please refer to the Data Sheet. Board layout examples are given in an application note.*

1) To generate the reference clock output for bus timing measurement, f_{SYS} must be selected as source for EXTCLK and P2.8 must be selected as output pin. Also the high-speed clock pad must be enabled. This configuration is referred to as reference clock output signal CLKOUT.

8 Kbytes of on-chip Stand-By SRAM (SBRAM) provide storage for system-relevant user data that must be preserved while the major part of the device is powered down. The SBRAM is accessed via a specific interface and is powered in domain M.

1024 bytes (2 × 512 bytes) of the address space are reserved for the Special Function Register areas (SFR space and ESFR space). SFRs are word-wide registers which are used to control and monitor functions of the different on-chip units. Unused SFR addresses are reserved for future members of the XE166 Family. In order to ensure upward compatibility they should either not be accessed or written with zeros.

The on-chip Flash memory stores code, constant data, and control data. The on-chip Flash memory consists of 1 module of 64 Kbytes (preferably for data storage) and modules with a maximum capacity of 256 Kbytes each. Each module is organized in sectors of 4 Kbytes.
The uppermost 4-Kbyte sector of segment 0 (located in Flash module 0) is used internally to store operation control parameters and protection information.

Note: The actual size of the Flash memory depends on the chosen device type.

Each sector can be separately write protected[1], erased and programmed (in blocks of 128 Bytes). The complete Flash area can be read-protected. A user-defined password sequence temporarily unlocks protected areas. The Flash modules combine 128-bit read access with protected and efficient writing algorithms for programming and erasing. Dynamic error correction provides extremely high read data security for all read access operations. Access to different Flash modules can be executed in parallel.
For Flash parameters, please see **Section 4.5**.

Memory Content Protection

The contents of on-chip memories can be protected against soft errors (induced e.g. by radiation) by activating the parity mechanism or the Error Correction Code (ECC).
The parity mechanism can detect a single-bit error and prevent the software from using incorrect data or executing incorrect instructions.
The ECC mechanism can detect and automatically correct single-bit errors. This supports the stable operation of the system.

It is strongly recommended to activate the ECC mechanism wherever possible because this dramatically increases the robustness of an application against such soft errors.

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1) To save control bits, sectors are clustered for protection purposes, they remain separate for programming/erasing.

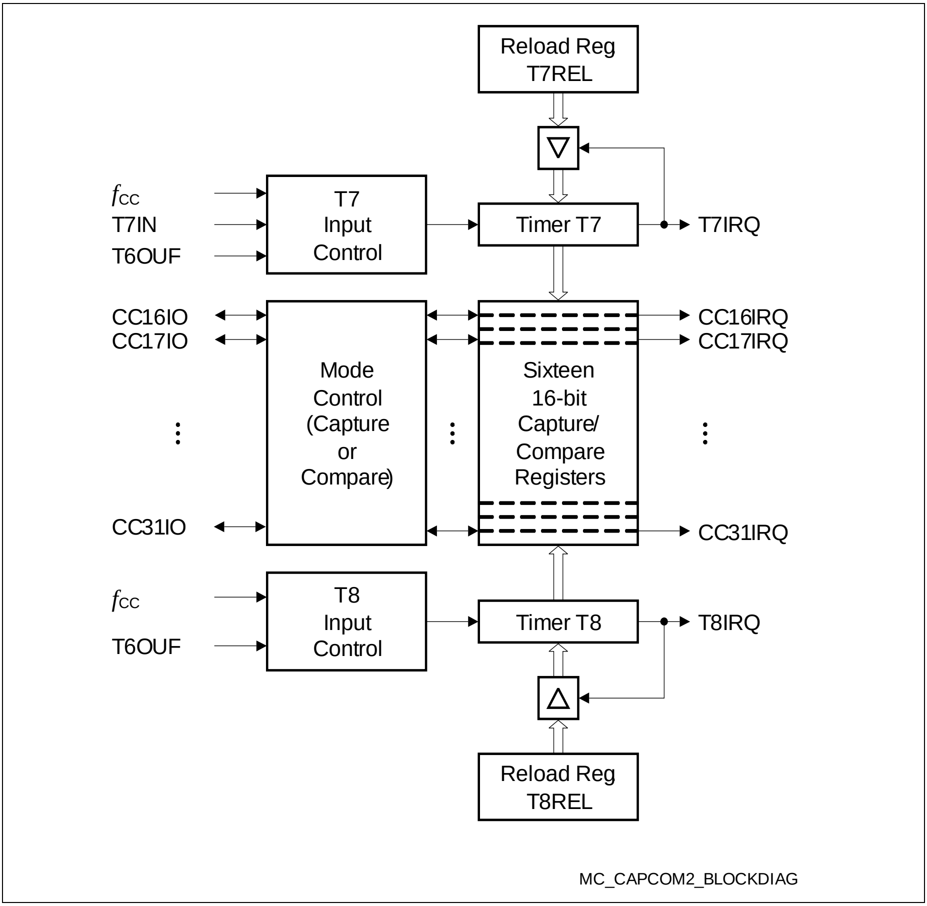
Reload Reg
T7REL
f_{CC}
T7IN
T6OUF
T7
Input
Control
Timer T7
T7IRQ
CC16IO
CC17IO
Mode
Control
(Capture
or
Compare)
Sixteen
16-bit
Capture/
Compare
Registers
CC16IRQ
CC17IRQ
CC31IO
CC31IRQ
f_{CC}
T6OUF
T8
Input
Control
Timer T8
T8IRQ
Reload Reg
T8REL
MC_CAPCOM2_BLOCKDIAG

Figure 6 CAPCOM2 Unit Block Diagram

3.10 General Purpose Timer (GPT12E) Unit

The GPT12E unit is a very flexible multifunctional timer/counter structure which can be used for many different timing tasks such as event timing and counting, pulse width and duty cycle measurements, pulse generation, or pulse multiplication.

The GPT12E unit incorporates five 16-bit timers organized in two separate modules, GPT1 and GPT2. Each timer in each module may either operate independently in a number of different modes or be concatenated with another timer of the same module.

Each of the three timers T2, T3, T4 of **module GPT1** can be configured individually for one of four basic modes of operation: Timer, Gated Timer, Counter, and Incremental Interface Mode. In Timer Mode, the input clock for a timer is derived from the system clock and divided by a programmable prescaler. Counter Mode allows timer clocking in reference to external events.

Pulse width or duty cycle measurement is supported in Gated Timer Mode, where the operation of a timer is controlled by the gate level on an external input pin. For these purposes each timer has one associated port pin (TxIN) which serves as a gate or clock input. The maximum resolution of the timers in module GPT1 is 4 system clock cycles.

The counting direction (up/down) for each timer can be programmed by software or altered dynamically by an external signal on a port pin (TxEUD), e.g. to facilitate position tracking.

In Incremental Interface Mode the GPT1 timers can be directly connected to the incremental position sensor signals A and B through their respective inputs TxIN and TxEUD. Direction and counting signals are internally derived from these two input signals, so that the contents of the respective timer Tx corresponds to the sensor position. The third position sensor signal TOP0 can be connected to an interrupt input.

Timer T3 has an output toggle latch (T3OTL) which changes its state on each timer overflow/underflow. The state of this latch may be output on pin T3OUT e.g. for time out monitoring of external hardware components. It may also be used internally to clock timers T2 and T4 for measuring long time periods with high resolution.

In addition to the basic operating modes, T2 and T4 may be configured as reload or capture register for timer T3. A timer used as capture or reload register is stopped. The contents of timer T3 is captured into T2 or T4 in response to a signal at the associated input pin (TxIN). Timer T3 is reloaded with the contents of T2 or T4, triggered either by an external signal or a selectable state transition of its toggle latch T3OTL. When both T2 and T4 are configured to alternately reload T3 on opposite state transitions of T3OTL with the low and high times of a PWM signal, this signal can be continuously generated without software intervention.

3.13 Universal Serial Interface Channel Modules (USIC)

The XE164xM features the USIC modules USIC0, USIC1, USIC2. Each module provides two serial communication channels.

The Universal Serial Interface Channel (USIC) module is based on a generic data shift and data storage structure which is identical for all supported serial communication protocols. Each channel supports complete full-duplex operation with a basic data buffer structure (one transmit buffer and two receive buffer stages). In addition, the data handling software can use FIFOs.

The protocol part (generation of shift clock/data/control signals) is independent of the general part and is handled by protocol-specific preprocessors (PPPs).

The USIC s input/output lines are connected to pins by a pin routing unit. The inputs and outputs of each USIC channel can be assigned to different interface pins, providing great flexibility to the application software. All assignments can be made during runtime.

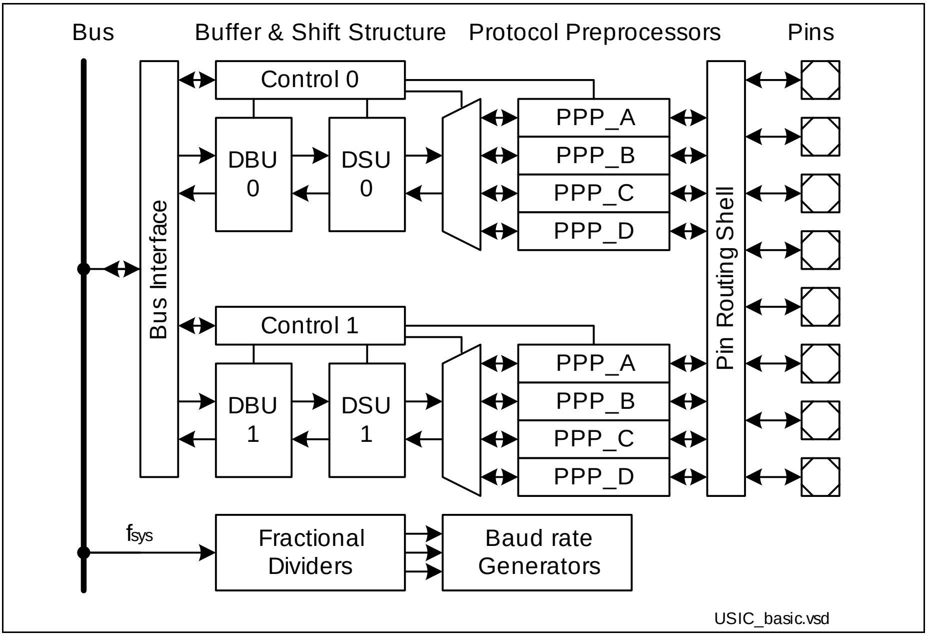
Bus
Buffer & Shift Structure
Protocol Preprocessors
Pins
Bus Interface
Control 0
DBU 0
DSU 0
PPP_A
PPP_B
PPP_C
PPP_D
Control 1
DBU 1
DSU 1
PPP_A
PPP_B
PPP_C
PPP_D
Pin Routing Shell
fsys
Fractional Dividers
Baud rate Generators
USIC_basic.vsd

Figure 11 General Structure of a USIC Module

The regular structure of the USIC module brings the following advantages:

Higher flexibility through configuration with same look-and-feel for data management
Reduced complexity for low-level drivers serving different protocols
Wide range of protocols with improved performances (baud rate, buffer handling)

3.16 Watchdog Timer

The Watchdog Timer is one of the fail-safe mechanisms which have been implemented to prevent the controller from malfunctioning for longer periods of time.

The Watchdog Timer is always enabled after an application reset of the chip. It can be disabled and enabled at any time by executing the instructions DISWDT and ENWDT respectively. The software has to service the Watchdog Timer before it overflows. If this is not the case because of a hardware or software failure, the Watchdog Timer overflows, generating a prewarning interrupt and then a reset request.

The Watchdog Timer is a 16-bit timer clocked with the system clock divided by 16,384 or 256. The Watchdog Timer register is set to a prespecified reload value (stored in WDTREL) in order to allow further variation of the monitored time interval. Each time it is serviced by the application software, the Watchdog Timer is reloaded and the prescaler is cleared.

Time intervals between 3.2 μs and 13.42 s can be monitored (@ 80 MHz).
The default Watchdog Timer interval after power-up is 6.5 ms (@ 10 MHz).

3.17 Clock Generation

The Clock Generation Unit can generate the system clock signal f_{SYS} for the XE164xM from a number of external or internal clock sources:

- External clock signals with pad voltage or core voltage levels
- External crystal or resonator using the on-chip oscillator
- On-chip clock source for operation without crystal/resonator
- Wake-up clock (ultra-low-power) to further reduce power consumption

The programmable on-chip PLL with multiple prescalers generates a clock signal for maximum system performance from standard crystals, a clock input signal, or from the on-chip clock source. See also **Section 4.6.2**.

The Oscillator Watchdog (OWD) generates an interrupt if the crystal oscillator frequency falls below a certain limit or stops completely. In this case, the system can be supplied with an emergency clock to enable operation even after an external clock failure.

All available clock signals can be output on one of two selectable pins.

Table 10 Instruction Set Summary (cont d)

Mnemonic	Description	Bytes
NOP	Null operation	2
CoMUL/CoMAC	Multiply (and accumulate)	4
CoADD/CoSUB	Add/Subtract	4
Co(A)SHR	(Arithmetic) Shift right	4
CoSHL	Shift left	4
CoLOAD/STORE	Load accumulator/Store MAC register	4
CoCMP	Compare	4
CoMAX/MIN	Maximum/Minimum	4
CoABS/CoRND	Absolute value/Round accumulator	4
CoMOV	Data move	4
CoNEG/NOP	Negate accumulator/Null operation	4

1) The Enter Power Down Mode instruction is not used in the XE164xM, due to the enhanced power control scheme. PWRDN will be correctly decoded, but will trigger no action.

Pullup/Pulldown Device Behavior

Most pins of the XE164xM feature pullup or pulldown devices. For some special pins these are fixed; for the port pins they can be selected by the application.

The specified current values indicate how to load the respective pin depending on the intended signal level. **Figure 13** shows the current paths.

The shaded resistors shown in the figure may be required to compensate system pull currents that do not match the given limit values.

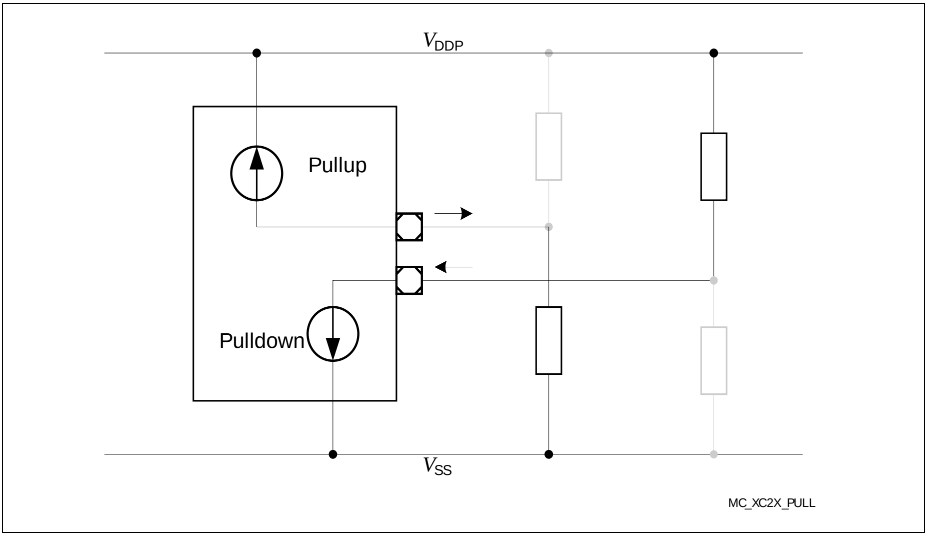

Figure 13 Pullup/Pulldown Current Definition

Table 17 ADC Parameters (cont d)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Broken wire detection delay against VAGND[2]	t_{BWG} CC	–	–	50	[3]	
Broken wire detection delay against VAREF[2]	t_{BWR} CC	–	–	50	[4]	
Conversion time for 8-bit result[2]	t_{c8} CC	(11 + STC) x t_{ADCI} + 2 x t_{SYS}				
Conversion time for 10-bit result[2]	t_{c10} CC	(13 + STC) x t_{ADCI} + 2 x t_{SYS}				
Total Unadjusted Error	|TUE| CC	–	1	2	LSB	[5]
Wakeup time from analog powerdown, fast mode[2]	t_{WAF} CC	–	–	4	µs	
Wakeup time from analog powerdown, slow mode[2]	t_{WAS} CC	–	–	15	µs	
Analog reference ground	V_{AGND} SR	V_{SS} - 0.05	–	1.5	V	
Analog input voltage range	V_{AIN} SR	V_{AGND}	–	V_{AREF}	V	[6]
Analog reference voltage	V_{AREF} SR	V_{AGND} + 1.0	–	V_{DDPA} + 0.05	V	[5]

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[1] These parameter values cover the complete operating range. Under relaxed operating conditions (room temperature, nominal supply voltage) the typical values can be used for calculation.

[2] This parameter includes the sample time (also the additional sample time specified by STC), the time to determine the digital result and the time to load the result register with the conversion result. Values for the basic clock t_{ADCI} depend on programming.

[3] The broken wire detection delay against V_{AGND} is measured in numbers of consecutive precharge cycles at a conversion rate of not more than 500 µs. Result below 10% (66 $_{\text{H}}$).

[4] The broken wire detection delay against V_{AREF} is measured in numbers of consecutive precharge cycles at a conversion rate of not more than 10 µs. This function is influenced by leakage current, in particular at high temperature. Result above 80% (332_{H}).

[5] TUE is tested at $V_{\text{AREF}} = V_{\text{DDPA}} = 5.0$ V, $V_{\text{AGND}} = 0$ V. It is verified by design for all other voltages within the defined voltage range. The specified TUE is valid only if the absolute sum of input overload currents on analog port pins (see I_{OV} specification) does not exceed 10 mA, and if V_{AREF} and V_{AGND} remain stable during the measurement time.

[6] V_{AIN} may exceed V_{AGND} or V_{AREF} up to the absolute maximum ratings. However, the conversion result in these cases will be X000_{H} or X3FF_{H}, respectively.

4.6.4 Pad Properties

The output pad drivers of the XE164xM can operate in several user-selectable modes. Strong driver mode allows controlling external components requiring higher currents such as power bridges or LEDs. Reducing the driving power of an output pad reduces electromagnetic emissions (EME). In strong driver mode, selecting a slower edge reduces EME.

The dynamic behavior, i.e. the rise time and fall time, depends on the applied external capacitance that must be charged and discharged. Timing values are given for a capacitance of 20 pF, unless otherwise noted.

In general, the performance of a pad driver depends on the available supply voltage V_{DDP}. The following table lists the pad parameters.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 30 EBC External Bus Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Output valid delay for $\overline{\text{RD}}$, $\overline{\text{WR}}$($\overline{\text{L}}$/$\overline{\text{H}}$)	t_{10} CC	–	11	20	ns	
Output valid delay for $\overline{\text{BHE}}$, ALE	t_{11} CC	–	10	21	ns	
Address output valid delay for A23 ... A0	t_{12} CC	–	11	22	ns	
Address output valid delay for AD15 ... AD0 (MUX mode)	t_{13} CC	–	10	22	ns	
Output valid delay for $\overline{\text{CS}}$	t_{14} CC	–	10	13	ns	
Data output valid delay for AD15 ... AD0 (write data, MUX mode)	t_{15} CC	–	10	22	ns	
Data output valid delay for D15 ... D0 (write data, DEMUX mode)	t_{16} CC	–	10	22	ns	
Output hold time for $\overline{\text{RD}}$, $\overline{\text{WR}}$($\overline{\text{L}}$/$\overline{\text{H}}$)	t_{20} CC	-2	8	10	ns	
Output hold time for $\overline{\text{BHE}}$, ALE	t_{21} CC	-2	8	10	ns	
Address output hold time for AD15 ... AD0	t_{23} CC	-3	8	10	ns	
Output hold time for $\overline{\text{CS}}$	t_{24} CC	-3	8	11	ns	
Data output hold time for D15 ... D0 and AD15 ... AD0	t_{25} CC	-3	8	10	ns	
Input setup time for READY, D15 ... D0, AD15 ... AD0	t_{30} SR	29	17	–	ns	
Input hold time READY, D15 ... D0, AD15 ... AD0[1]	t_{31} SR	0	-9	–	ns	

[1] Read data are latched with the same internal clock edge that triggers the address change and the rising edge of $\overline{\text{RD}}$. Address changes before the end of $\overline{\text{RD}}$ have no impact on (demultiplexed) read cycles. Read data can change after the rising edge of $\overline{\text{RD}}$.

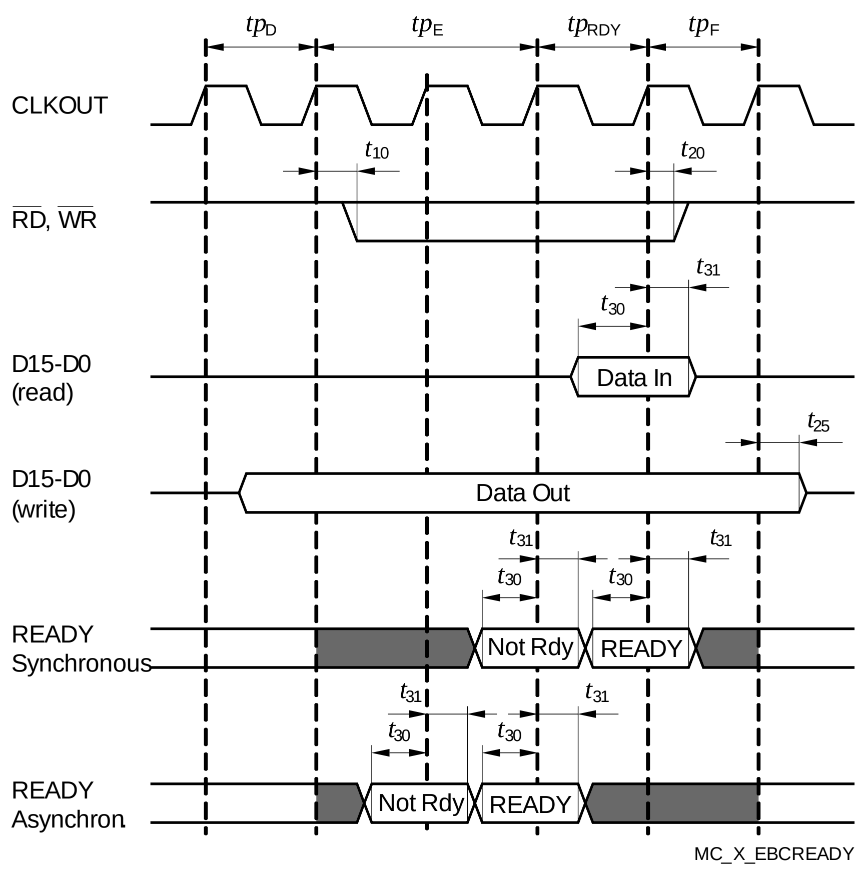
tpD
tpE
tpRDY
tpF
CLKOUT
t10
t20
RD, WR
t31
t30
D15-D0 (read)
Data In
t25
D15-D0 (write)
Data Out
t31
t30
t31
t30
READY Synchronous
Not Rdy
READY
t31
t30
t31
t30
READY Asynchron.
Not Rdy
READY
MC_X_EBCREADY

Figure 25 READY Timing

Note: If the READY input is sampled inactive at the indicated sampling point ("Not Rdy") a READY-controlled waitstate is inserted (tpRDY),
sampling the READY input active at the indicated sampling point ("Ready") terminates the currently running bus cycle.
Note the different sampling points for synchronous and asynchronous READY.
This example uses one mandatory waitstate (see tpE) before the READY input value is used.

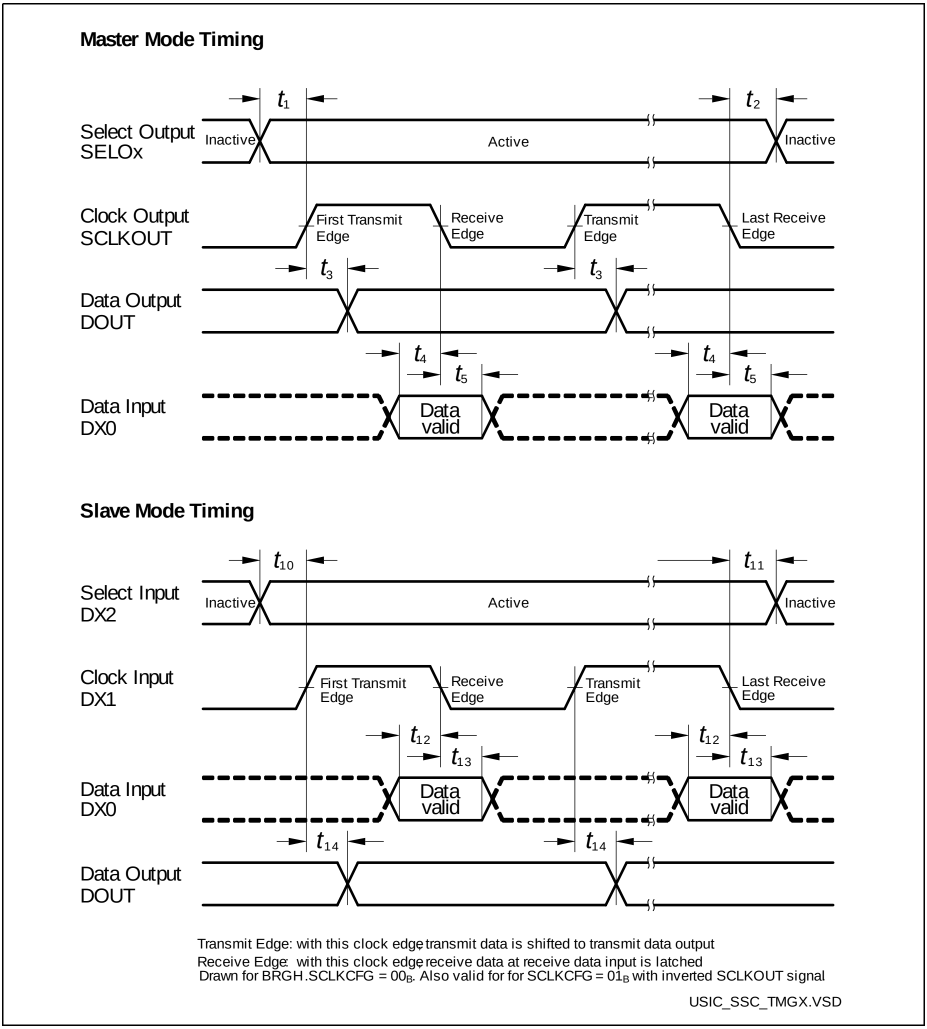
Master Mode Timing
t1
t2
Select Output SELOx
Inactive
Active
Inactive
Clock Output SCLKOUT
First Transmit Edge
Receive Edge
Transmit Edge
Last Receive Edge
t3
t3
Data Output DOUT
t4
t5
t4
t5
Data Input DX0
Data valid
Data valid
Slave Mode Timing
t10
t11
Select Input DX2
Inactive
Active
Inactive
Clock Input DX1
First Transmit Edge
Receive Edge
Transmit Edge
Last Receive Edge
t12
t13
t12
t13
Data Input DX0
Data valid
Data valid
t14
t14
Data Output DOUT
Transmit Edge: with this clock edge, transmit data is shifted to transmit data output
Receive Edge: with this clock edge, receive data at receive data input is latched
Drawn for BRGH.SCLKCFG = 00B. Also valid for for SCLKCFG = 01B with inverted SCLKOUT signal
USIC_SSC_TMGX.VSD

Figure 26 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration where the slave select signal is low-active and the serial clock signal is not shifted and not inverted.

Debug via JTAG

The following parameters are applicable for communication through the JTAG debug interface. The JTAG module is fully compliant with IEEE1149.1-2000.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply; C_L= 20 pF.

Table 37 JTAG Interface Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK clock period	t_1 SR	50[1]	–	–	ns	[2]
TCK high time	t_2 SR	16	–	–	ns	
TCK low time	t_3 SR	16	–	–	ns	
TCK clock rise time	t_4 SR	–	–	8	ns	
TCK clock fall time	t_5 SR	–	–	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	
TDI/TMS hold after TCK rising edge	t_7 SR	6	–	–	ns	
TDO valid from TCK falling edge (propagation delay)[3]	t_8 CC	–	25	29	ns	
TDO high impedance to valid output from TCK falling edge[4][3]	t_9 CC	–	25	29	ns	
TDO valid output to high impedance from TCK falling edge[3]	t_{10} CC	–	25	29	ns	
TDO hold after TCK falling edge[3]	t_{18} CC	5	–	–	ns	

[1] The debug interface cannot operate faster than the overall system, therefore $t_1 \geq t_{SYS}$.

[2] Under typical conditions, the interface can operate at transfer rates up to 20 MHz.

[3] The falling edge on TCK is used to generate the TDO timing.

[4] The setup time for TDO is given implicitly by the TCK cycle time.

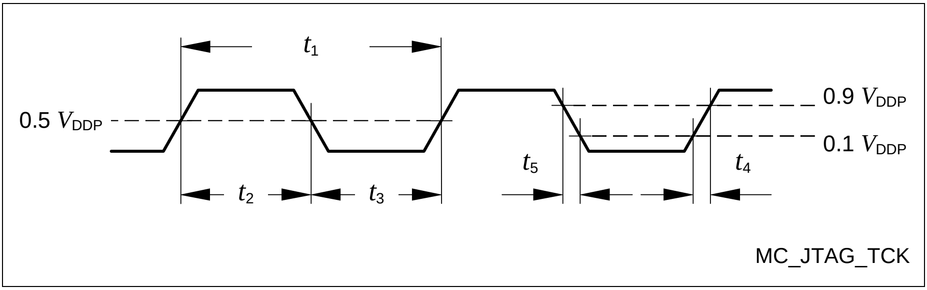
t_1
0.5 V_{DDP}
0.9 V_{DDP}
0.1 V_{DDP}
t_2
t_3
t_5
t_4
MC_JTAG_TCK

Figure 30 Test Clock Timing (TCK)

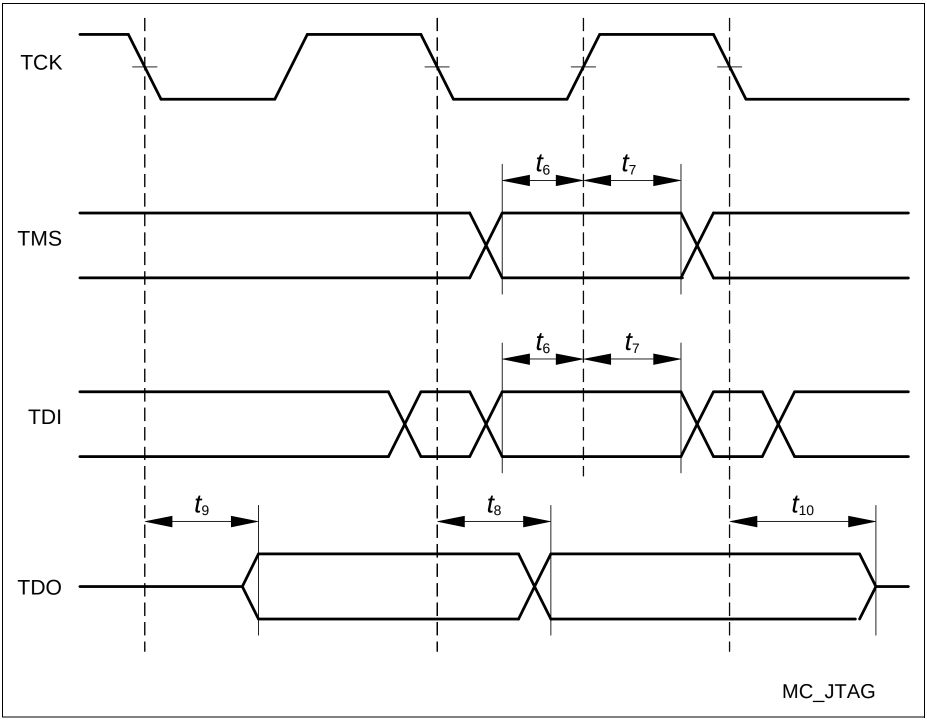
TCK
TMS
TDI
TDO
t_6
t_7
t_6
t_7
t_9
t_8
t_{10}
MC_JTAG

Figure 31 JTAG Timing